

HQ:NSC14/No AI

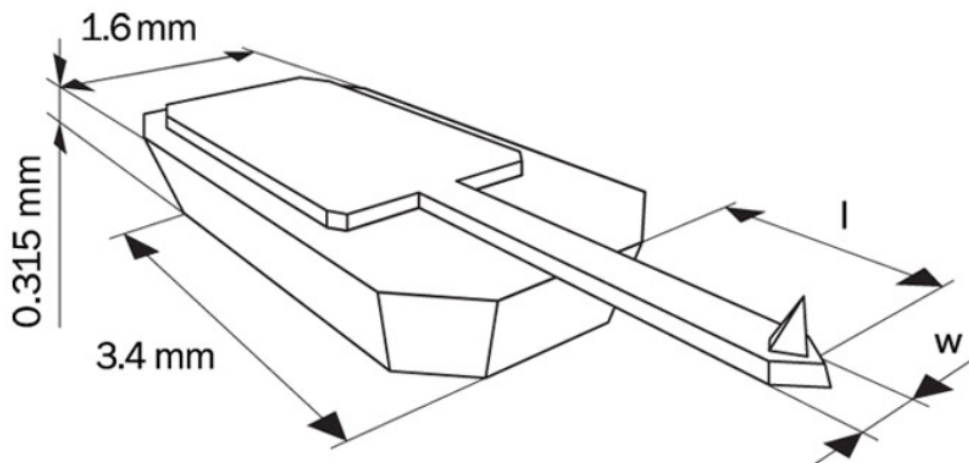
Soft Tapping Mode AFM Probe

AFM probes of the HQ:NSC14 series are generally used in tapping mode for imaging relatively soft samples to obtain better phase contrast and reduce surface deformations caused by the tapping AFM tip.

The HQ AFM probes offer high consistency of the AFM tip radius, the AFM cantilever reflectivity and the quality factor.

Coating

none



AFM Probe Specifications

AFM Tip

SHAPE	HEIGHT	FULL CONE ANGLE	RADIUS
Rotated	15 μm (12 – 18 μm)*	40°	< 8 nm

AFM Cantilever

CANTILEVER	SHAPE	FORCE CONST.	RES. FREQ.	LENGTH	WIDTH	THICKNESS
Cantilever A	Beam	5 N/m (1.8 – 13 N/m)*	160 kHz (110 – 220 kHz)*	125 μm (1 – 130 μm)*	25 μm (22 – 28 μm)*	2.1 μm (1.6 – 2.6 μm)*

* typical values